

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1334	((serializer/deserializer) or serdes or (serial\$5 near2 deserial\$5))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/06/18 09:31
L2	236	((serializer/deserializer) or serdes or (serial\$5 near2 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or jitter))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/06/18 09:32
L3	292	((serializer/deserializer) or serdes or (serial\$5 near2 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or jitter or (pattern near2 generat\$5)))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/06/18 09:59
L4	40	((serializer/deserializer) or serdes or (serial\$5 near2 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or jitter or (pattern near2 generat\$5))) and (CDR or (clock near2 data near2 recover\$3))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/06/18 10:02
L5	73	((serializer/deserializer) or serdes or (serial\$5 near2 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or jitter or test\$3 or (pattern near2 generat\$5))) and (CDR or (clock near2 data near2 recover\$3))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/06/18 10:02
L6	257	((serializer/deserializer) or serdes or (serial\$5 near2 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or jitter or test\$3 or (pattern near2 generat\$5))) and (CDR or (clock near2 data near2 recover\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:02
L7	248	((serializer/deserializer) or serdes or (serial\$5 near2 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or jitter or test\$3 or (pattern near2 generat\$5))) and (CDR or (clock near2 data near2 recover\$3)) and (multiplex\$3 or MUX or switch\$3 or select\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:03
L8	180	((serializer/deserializer) or serdes or (serial\$5 near2 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or jitter or test\$3 or (pattern near2 generat\$5))) and (CDR or (clock near2 data near2 recover\$3)) and (multiplex\$3 or MUX or switch\$3 or select\$3) and delay\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:04

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L9	27	((serializer/deserializer) or serdes or (serial\$5 near2 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or jitter or test\$3 or (pattern near2 generat\$5))) and (CDR or (clock near2 data near2 recover\$3)) and (multiplex\$3 or MUX or switch\$3 or select\$3) and (delay\$3 near2 (circuit\$1 or means or unit\$1))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:27
L10	10	((serializer/deserializer) or serdes or (serial\$5 near2 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or test\$3 or (pattern near2 generat\$5))) and (CDR or (clock near2 data near2 recover\$3)) and (multiplex\$3 or MUX or switch\$3 or select\$3) and (delay\$3 near2 (circuit\$1 or means or unit\$1)) and jitter	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:27
L11	12	((serializer/deserializer) or serdes or (serial\$5 near10 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or test\$3 or (pattern near2 generat\$5))) and (CDR or (clock near2 data near2 recover\$3)) and (multiplex\$3 or MUX or switch\$3 or select\$3) and (delay\$3 near2 (circuit\$1 or means or unit\$1)) and jitter	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:28
L12	21	((serializer/deserializer) or serdes or (serial\$5 near10 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or test\$3 or (pattern near2 generat\$5))) and (CDR or (clock near2 data near2 recover\$3)) and (multiplex\$3 or MUX or switch\$3 or select\$3) and (delay\$3 near2 (circuit\$1 or means or unit\$1))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:28
L13	9	((serializer/deserializer) or serdes or (serial\$5 near10 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or test\$3 or (pattern near2 generat\$5))) and (CDR or (clock near2 data near2 recover\$3)) and (multiplex\$3 or MUX\$2) and (delay\$3 near2 (circuit\$1 or means or unit\$1))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:30

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L14	220	((serializer/deserializer) or serdes or (serial\$5 near10 deserial\$5)) and ((self-test or (self near2 test\$3) or BIST or test\$3 or (pattern near2 generat\$5))) and (CDR or (clock near2 data near2 recover\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:30
L15	19	((serializer/deserializer) or serdes or (serial\$5 near10 deserial\$5)) same ((self-test or (self near2 test\$3) or BIST or test\$3 or (pattern near2 generat\$5))) same (CDR or (clock near2 data near2 recover\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:36
L16	10	((serializer/deserializer) or serdes or (serial\$5 same deserial\$5)) and ((self-test or (self adj2 test\$3) or BIST or (pattern near2 generat\$5))) and ((CDR or (clock adj1 data adj1 recover\$3)) adj2 (circuit or unit or device or means))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:39
L17	20	((serializer/deserializer) or serdes or serial\$5 or deserial\$5) and ((self-test or (self adj2 test\$3) or BIST or (pattern near2 generat\$5))) and ((CDR or (clock adj1 data adj1 recover\$3)) adj2 (circuit or unit or device or means))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:42
L18	504	((serializer/deserializer) or serdes or serial\$5 or deserial\$5) and ((self-test or (self adj2 test\$3) or BIST or (pattern near2 generat\$5))) and (CDR or (clock adj1 data adj1 recover\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/18 10:43
L19	255	((serializer/deserializer) or serdes or serial\$5 or deserial\$5) and ((self-test or (self adj2 test\$3) or BIST or (pattern near2 generat\$5))) and (CDR or (clock adj1 data adj1 recover\$3))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/06/18 10:43
L20	13	((serializer/deserializer) or serdes or (serial\$5 same deserial\$5)) and ((self-test or (self adj2 test\$3) or BIST or (pattern near2 generat\$5))) and (CDR or (clock adj1 data adj1 recover\$3))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/06/18 10:55
L21	254	((serializer/deserializer) or serdes or (serial\$5 same deserial\$5)) and ((self-test or (self adj2 test\$3) or BIST or (pattern near2 generat\$5)))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/06/18 10:55

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L22	44	((serializer/deserializer) or serdes or (serial\$5 same deserial\$5)) same ((self-test or (self adj2 test\$3) or BIST or (pattern near2 generat\$5)))	USPAT; EPO; JPO; DERWENT	OR	OFF	2006/06/18 10:56
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Day : Sunday
Date: 6/18/2006

Time: 10:13:02

 **PALM INTRANET**

Inventor Name Search Result

Your Search was:

Last Name = BONNEAU

First Name = DOMINIQUE

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<u>07680490</u>	<u>5155572</u>	150	04/04/1991	VERTICAL ISOLATED-COLLECTOR PNP TRANSISTOR STRUCTURE	BONNEAU, DOMINIQUE
<u>09304608</u>	<u>6111471</u>	150	05/04/1999	APPARATUS AND METHOD FOR SETTING VCO FREE-RUNNING FREQUENCY	BONNEAU, DOMINIQUE
<u>09745988</u>	<u>6834367</u>	150	12/21/2000	BUILT-IN SELF TEST SYSTEM AND METHOD FOR HIGH SPEED CLOCK AND DATA RECOVERY CIRCUIT	BONNEAU, DOMINIQUE P.
<u>10707961</u>	Not Issued	30	01/28/2004	SERIALIZER/DESERIALIZER CIRCUIT FOR JITTER SENSITIVITY CHARACTERIZATION	BONNEAU, DOMINIQUE P.

Inventor Search Completed: No Records to Display.

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BONNEAU DOMINIQUE Search

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Day : Sunday
Date: 6/18/2006

Time: 10:13:11

PALM INTRANET

Inventor Name Search Result

Your Search was:

Last Name = HAUVILLER

First Name = PHILIPPE

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<u>07249542</u>	<u>4918448</u>	150	09/26/1988	DEVICE FOR EXTENDING THE RESOLUTION OF A N-BIT RESISTIVE DIGITAL-TO-ANALOG CONVERTER TO A (N+P)-BIT DIGITAL-TO-ANALOG CONVERTER	HAUVILLER, PHILIPPE
<u>09745988</u>	<u>6834367</u>	150	12/21/2000	BUILT-IN SELF TEST SYSTEM AND METHOD FOR HIGH SPEED CLOCK AND DATA RECOVERY CIRCUIT	HAUVILLER, PHILIPPE
<u>10280286</u>	Not Issued	93	10/24/2002	TRANSITION DETECTION, VALIDATION AND MEMORIZATION CIRCUIT	HAUVILLER, PHILIPPE
<u>10280287</u>	Not Issued	71	10/24/2002	Sample selection and data alignment circuit	HAUVILLER, PHILIPPE
<u>10707961</u>	Not Issued	30	01/28/2004	SERIALIZER/DESERIALIZER CIRCUIT FOR JITTER SENSITIVITY CHARACTERIZATION	HAUVILLER, PHILIPPE
<u>10738347</u>	<u>6946986</u>	150	12/17/2003	DIFFERENTIAL SAMPLING CIRCUIT FOR GENERATING A DIFFERENTIAL INPUT SIGNAL DC OFFSET	HAUVILLER, PHILIPPE
<u>10904691</u>	Not Issued	30	11/23/2004	IMPROVEMENTS TO DATA RECOVERY CIRCUITS USING OVERSAMPLING FOR ISI COMPENSATION	HAUVILLER, PHILIPPE
<u>10906988</u>	Not Issued	30	03/15/2005	AN IMPROVED RECEIVER HAVING FULL SIGNAL PATH DIFFERENTIAL OFFSET CANCELLATION CAPABILITIES	HAUVILLER, PHILIPPE

Inventor Search Completed: No Records to Display.

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Search Another: Inventor	<input type="text" value="HAUVILLER"/>	<input type="text" value="PHILIPPE"/>	<input type="button" value="Search"/>

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Day : Sunday
Date: 6/18/2006


PALM INTRANET

Time: 10:13:16

Inventor Name Search Result

Your Search was:

Last Name = VALLET

First Name = VINCENT

Application#	Patent#	Status	Date Filed	Title	Inventor Name
07730736	5112765	150	07/16/1991	METHOD OF FORMING STACKED TUNGSTEN GATE PFET DEVICES AND STRUCTURES RESULTING THEREFROM	VALLET, VINCENT
09304608	6111471	150	05/04/1999	APPARATUS AND METHOD FOR SETTING VCO FREE-RUNNING FREQUENCY	VALLET, VINCENT
09745988	6834367	150	12/21/2000	BUILT-IN SELF TEST SYSTEM AND METHOD FOR HIGH SPEED CLOCK AND DATA RECOVERY CIRCUIT	VALLET, VINCENT
10280285	Not Issued	93	10/24/2002	METHOD AND CIRCUIT FOR RECOVERING A DATA SIGNAL FROM A STREAM OF BINARY DATA	VALLET, VINCENT
10280286	Not Issued	93	10/24/2002	TRANSITION DETECTION, VALIDATION AND MEMORIZATION CIRCUIT	VALLET, VINCENT
10280287	Not Issued	71	10/24/2002	Sample selection and data alignment circuit	VALLET, VINCENT
10707961	Not Issued	30	01/28/2004	SERIALIZER/DESERIALIZER CIRCUIT FOR JITTER SENSITIVITY CHARACTERIZATION	VALLET, VINCENT
10904691	Not Issued	30	11/23/2004	IMPROVEMENTS TO DATA RECOVERY CIRCUITS USING OVERSAMPLING FOR ISI COMPENSATION	VALLET, VINCENT
10904693	Not Issued	30	11/23/2004	IMPROVEMENTS TO DATA RECOVERY CIRCUITS USING OVERSAMPLING FOR BEST DATA SAMPLE SELECTION	VALLET, VINCENT

<u>11160755</u>	Not Issued	30	07/07/2005	DATA RECOVERY CIRCUITS USING OVERSAMPLING FOR MAVERICK EDGE DETECTION/SUPPRESSION	VALLET, VINCENT
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Inventor Search Completed: No Records to Display.

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